

| Search Notes | Application/Control No. | Applicant(s)/Patent under Reexamination |
|-----------------|-------------------------|---|
| | 10/005,959 | PEEV ET AL. |
| Examiner | Art Unit | |
| J. Derek Rutten | 2192 | |

| SEARCH NOTES (INCLUDING SEARCH STRATEGY) | | |
|---|-----------|------|
| | DATE | EXMR |
| EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB) - see search history printout | 8/17/2005 | JDR |
| 717/168-178 - text search only - see search history printout | 8/23/2005 | JDR |
| EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB) - see search history printout | 8/23/2005 | JDR |
| USPN 6366898 | 8/24/2005 | JDR |
| Chameli Das (consulted re. allowability) | 9/9/2005 | JDR |
| ACM - portal.acm.org IEEE - ieeexplore.ieee.org (see search history printout) | 9/9/2005 | JDR |
| EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB) - see search history printout | 9/9/2005 | JDR |

| INTERFERENCE SEARCHED | | | |
|-----------------------|----------|----------|----------|
| Class | Subclass | Date | Examiner |
| 717 | 136,174 | 9/9/2005 | JDR |
| 707 | 202 | 9/9/2005 | JDR |
| 704 | 15 | 9/9/2005 | JDR |
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